## Search Notes



Application/Control No.	Applicant(s)/Patent Under Reexamination	
10644445	ANDERSON ET AL.	
Examiner	Art Unit	
Chawan, Sheela C	2624	

SEARCHED					
Class	Subclass	Date	Examiner		
382	187, 174,177, 203,289,	1/29/07	SCC		
709	217-219,229-232,211-212,247	11	11		
711	161-162	11	11		
216	24,33,41,52		11		
725	135,138,32, 90	"	11		
715	758	**	11		
ABOVE SEARCH UP- DATE.		3/31/07	SCC		

SEARCH NOTES				
Search Notes	Date	Examiner		
EAST, US-PGPUB, USPAT, EPO., JPO, DERWENT, IBM-TDB.	1/29/07	SCC		
INVENTOR NAME SEARCH.	11	"		
SEARCH EAST, AND OTHER DATABASE SEE THE ATTACHED SEARCH HISTORY.	3/31/07	scc		
382/187,177.CCLS.US-PATENT ONLY SEE TEXT SEARCH.	3/31/07	SCC		
709/212,231,247.CCLS. "	3/31/07	SCC		
INTERFERENCE SEARCH, SEE SEARCH HISTORY PRINT OUT.	3/31/07	SCC		
SEARCH IEEE OR INSPEC DATABASE.	3/31/07	SCC		

INTERFERENCE SEARCH					
Class	Subclass	Date	Examiner		
382	187	3/31/07	SCC		
709	212,231,247	3/31/07	SCC		